



DEFENSE LOGISTICS AGENCY
LAND AND MARITIME
POST OFFICE BOX 3990
COLUMBUS, OH 43218-3990

September 2nd, 2025

Paul Kamper
Quality Manager
Micross STS (Hi-Reliability Microelectronics)
1804 McCarthy Blvd
Milpitas, CA 95035

Dear Mr. Kamper:

Re: Commercial Laboratory Suitability Status; MIL-STD-883; FSC 5962; VQC-25-039763; Abel. CN: 092849.

Micross STS (Hi-Reliability Microelectronics) has demonstrated compliance to MIL-STD-883, the test standard for integrated circuits, to the DLA Land & Maritime. This letter is revised to reflect the status of Micross STS (Hi-Reliability Microelectronics) Commercial Laboratory Suitability, for the test methods and conditions shown in the enclosure. All testing on monolithic microcircuits shall be performed in accordance with the requirements of military specification MIL-PRF-38535 effective immediately. This letter supersedes DLA Land and Maritime-VQC-23-037554 to reflect the current suitability status.

Your laboratory is to maintain a record for all microcircuit testing and submit a three-part summary annually to DLA Land and Maritime-VQC that will include the following three parts as a minimum:

1. Retention Report
 - a. Military Part Number
 - b. Vendor Part Number
 - c. Manufacturer/ Customer
 - d. Lot Date Code
 - e. Test Method(s) and Specified Conditions
 - f. Date Test Completed
 - g. Quantity Tested
 - h. Quantity Accepted and Rejected, when evaluating Acceptability
2. Summary of MIL-STD-883 Internal Audit Results
3. Master List of Controlled Documents (External and Internal), including Current Revision

The standard retention-reporting period is the calendar year, from 01 JAN through 31 DEC. Your three-part report is then due by 31 JAN the following year.

Test labs shall notify the qualifying activity immediately after learning of a potential issuance of a GIDEP alert, problem advisory or major quality/reliability problem on their military products utilizing the test methods on the attached enclosure. Failure to provide prior notification may be grounds for removal from DLA Land and Maritime's Commercial Lab Suitability Listing.

This Laboratory Suitability is subject to the policies, procedures, and conditions of the Defense Standardization Program, as published in the manual DoD 4120.24-M, SD-6, and the DLA Land and Maritime-VQ Laboratory Suitability Booklet.

This laboratory suitability is valid until withdrawn by DLA Land and Maritime-VQC. Any deviation to the test method or condition(s) listed herein must be approved by the Qualifying Activity.

If you have any questions, please contact Mr. Jerrod Abel at (614) 692-9933.

Sincerely,

MICHAEL S. ADAMS

Chief

Custom Devices Branch

Enclosure

Visit us on the web at: http://landandmaritimeapps.dla.mil/offices/sourcing_and_qualification/

<u>TEST</u>	<u>METHOD/CONDITION</u>
Insulation Resistance	1003 (A-E, 600V, 100na)
Moisture Resistance	1004
Steady State Life Test	1005 (A-F, Ta, Tc)
Stabilization Bake	1008 (A-D)
Salt Atmosphere	1009 (A-D)
Temperature Cycling	1010 (A-C)
Thermal Shock	1011 (A-C)
Seal	1014 (A ₁ , A ₂ , C ₁)
Burn-in	1015 (A-F, Ta, Tc)
Constant Acceleration	2001 (A-E)
Mechanical Shock	2002 (A-G)
Solderability	2003 (Test A-C)
Lead Integrity	2004 (A, A ₁ , B ₁ , B ₂ , D, E)
Vibration, Variable Frequency	2007 (A-C)
External Visual	2009
Internal Visual	2010 (A, B)
Bond Strength	2011 (D)
Radiography	2012
Internal Visual Inspection for DPA	2013
Internal Visual & Mechanical	2014
Resistance to Solvents	2015
Physical Dimensions	2016
Internal Visual (Hybrid)	2017
Die Shear Strength	2019
Particle Impact Noise Detection (PIND)	2020 (A, B)
Nondestructive Bond Pull	2023
Lid Torque for Glass Frit Sealed Packages	2024
Adhesion of Lead Finish	2025
Random Frequency Vibration	2026
Substrate Attach Strength	2027
Pin Grid Destructive Lead Pull	2028
Ultrasonic Inspection of Die Attach	2030
Flip Chip Pull-off Test	2031
Visual Inspection of Passive Elements	2032
Resistance to Soldering Heat	2036 (A, B, I, J, K)
Solder Column Package Destructive Lead Pull	2038
ESDS Classification	3015
Latch-Up	3023 (JESD78)
Electrical Test	Per MIL-STD-883 para. 4.5
Highly Accelerated Temperature & Humidity Stress Test (HAST)	JESD22-A110 (Continuous Power Only)
Accelerated Moisture Resistance - Unbiased HAST	JESD22-A118

